

#### PCN# 20121123000

Qualification of CLARK-AT as new assembly site for affected device(s) moving from SCSAT, corresponding package change from punched RTC to sawn RGZ and change of orderable part number(s) Change Notification / Sample Request

 Date:
 11/26/2012

 To:
 Newark PCN

Dear Customer:

This is an announcement of change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. If you require samples to conduct an evaluation, please make any request within the 30 days—samples are not built ahead of the change. Please see the schedule on the following pages for availability dates. You may contact the PCN Manager or your local Field Sales Representative to acknowledge this PCN and request samples.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process. Any negotiated alternative change requirements will be provided via the customer's defined process. Customers with previously negotiated, special requirements will be handled separately. Any inquiries should be directed to your local Field Sales Representative.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (<u>PCN ww admin team@list.ti.com</u>).

Sincerely,

PCN Team SC Business Services Phone: +1(214) 480-6037 Fax: +1(214) 480-6659

#### 20121123000 Attachment: 1

#### **Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

### DEVICE

CC2420RTC

# CUSTOMER PART NUMBER

null

Technical details of this Product Change follow on the next page(s).

PCN Number: 20			21123000			PCN Dat	e:	11	/26/2012
Title:Qualification of CLARK-AT as new assembly site for affected device(s) moving from SCSAT, corresponding package change from punched RTC to sawn RGZ and change of orderable part number(s)									
Customer Contact:PCN_ww_admin_team@list.ti.comPhone:+1(214)480-6037Dept:Quality Services					<b>~</b> ,				
Proposed 1 <sup>st</sup> Ship Date:			02/26/2013	<b>Estimated Sample Availability</b>		y:	01	/26/2013	
Change Type:									
Assembly Site Assembly Process Assembly Materials			S						
Design Electrical Specification Mechanical Specification			ication						
Test Site Packing/Shipp			oing/Label	ing	Test Process				
🔲 Wafer Bump Site 📃 Wafer Bump N		Material		Wafer Bump Process					
Wafer Fab Site Wafer Fab Mate			iterials		Wafer Fab	Proc	cess	5	
PCN Details									

#### **Description of Change:**

Texas Instruments is pleased to announce the ongoing qualification of its CLARK-AT facility as a new assembly site for 7x7 mm, 48-pin RTC VQFN packaged device(s) currently being assembled at its SCSAT subcon facility. A package change (see package mechanical drawings) and an orderable part number change will accompany this change. The sawn RGZ package is considered backwards compatible with the punched RTC package, i.e. no PCB footprint change is necessary. Please see the tables below for further details on site and associated RoHS compliant and REACH compliant bill of material changes. Packing materials (shipping boxes, tape & reels, trays, etc.) at the additional site will be consistent with materials currently in use at that added site.

	Current (RTC)	Qualification (RGZ)
Assembly Site	SCSAT	CLARK-AT
Package Designator	RTC	RGZ
Leadframe	SID#R002-2072X (NiPdAu)	4211075-0001 (NiPdAu)
Mount Compound	SID#R008-0097X	4207123-0002
Mold Compound	SID#R003-0301X	4208625-0005
Bond Wire	SID#R005-0077X 25.4 µm (1 mil Au)	4072459-5000 (0.96 mil
		Au)

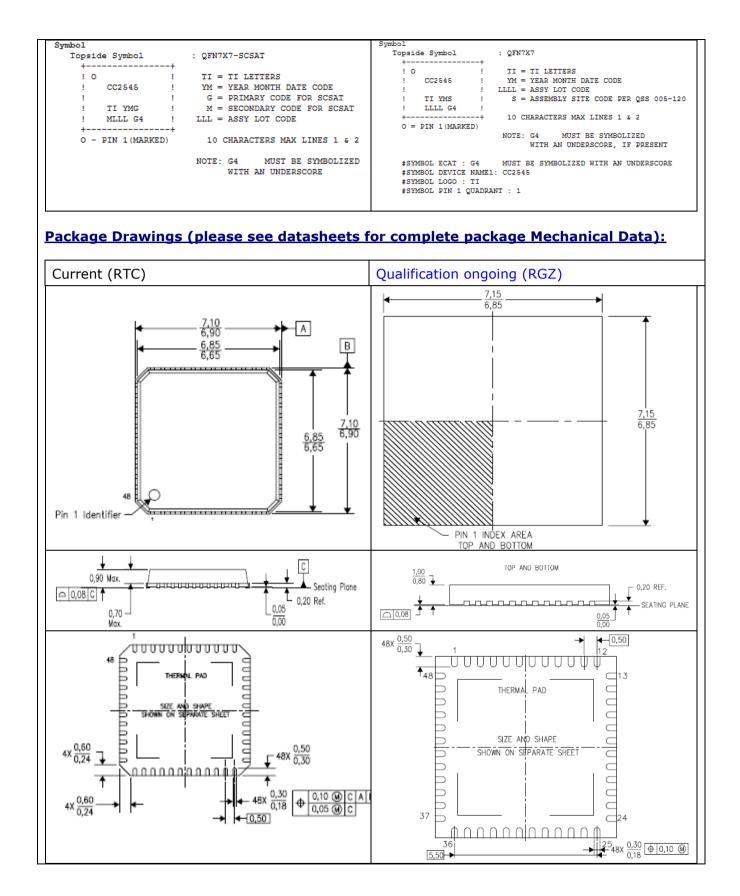
#### **Device Names / Orderables**

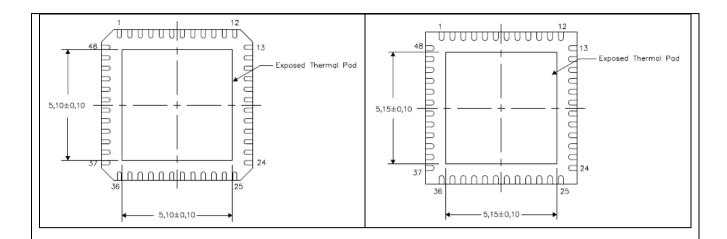
The orderable part number will change to reflect the RGZ package designator. Customers must convert their systems over to the new part numbers when this PCN goes into effect. The "Package Option Addendum" section in the updated datasheet as well as product information page on web will reflect these orderable device changes when they go into effect.

#### Package marking:

Current (RTC)

Qualification ongoing (RGZ)





## Tube related changes:

	Current (RTC / -RTB1)	Qualification (RGZ)
Standard Pack Quantity (SPQ)	43	52
Minimum Pack Quantity (MOQ)	258	2080
Ship tube	SID#R020-0395X	4204830-0005
End Plug 1	SID#R020-0395X (gray)	4203950-0020 (green)
End plug 2	SID#R020-0395X (gray)	4203950-0021 (white)
Ship bag	SID#B050-0138X	4200734-0023
Ship box	SID#B002-0427X L/W/H: 556mm / 162mm / 98mm	4204976-0001 L/W/H: 407mm/104mm/97mm

#### **Reason for Change:**

Continuity of Supply

Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):

Improved reliability by changing to sawn RGZ package with higher package integrity.

Changes to product identification resulting from this PCN:

### Shipment Labels:

#### Current

Assembly Site	Assembly site Origin (22L)	Assembly country Origin (23L)
SCSAT	STS	SGP
New		
Assembly Site	Assembly site Origin (22L)	Assembly country Origin (23L)
CLARK-AT	QAB	PHL

Sample product shipping label TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 2Q: MSL '2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/0 OPT:		(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483512 (P)
LBL: 5A (L)T0:1750		(2P) REV: (V) 0033317 (20L) CSO:SHE (21L) CCO:USA (22L) ASO:MLA (23L) ACO:MYS
Product Affected: Current Part number	New Part Number	

Current Part number	New Part Number
CC2420-RTB1	CC2420RGZ
CC2420-RTR1	CC2420RGZR
CC2420RTC	CC2420RGZ
CC2420RTCR	CC2420RGZR
CC2420RTCT	CC2420RGZT
CC2420Z-RTB1	CC2420RGZ
CC2420ZRTC	CC2420RGZ
CC2420ZRTCR	CC2420RGZR
CC2545RTCR	CC2545RGZR
CC2545RTCT	CC2545RGZT
EM2420-RTR1	EM2420RGZR
EM2420RTCR	EM2420RGZR
FRE005RTCR	FRE005RGZR
FRE005RTCT	FRE005RGZT
	Qualification Data

# **Qualification Data:**

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.					
Qualification Schedule:	Start:	2012-10-15	End:	2013-02-05	
<b>Qualification Device Constr</b>	uction Det	ails:			
Device:         See the Product Affected section of this document for a list of qualified devices         Qual device 1 for QBS					
Wafer Fab:TSMC Fab11TSMC Fab11				TSMC Fab11	
Wafer Technology:	0.18um CMOS		0.18um CMOS		
Assembly Site:	CLARK-AT			SCS-AT	
Package Type/Code:	48VQFN / RGZ		48VQFN / RTC		
Package Pins:	48		48		
Mold Compound:	4208625-0005		SID#R003-0301X		
Lead Frame:	4211075-0001		SID#R002-2072X		
Composition:	NiPdAu, Cu base		NiPdAu, Cu base		
Die Attach:	4207123-0002		SID#R008-0097X		
Wire Diameter:	24.3 um (0.96 mils)		25.4 um (1.00 mils)		
Moisture Level:	Ν	1SL3 / 260°C	1	MSL3 / 260°C	

Qualification: 🛛 🛛 Pla	n 🗌 Test Results	
Reliability Test	Conditions	Sample Size
•		(PASS/FAIL)
SD HBM	Human Body Model	9/0
	JEDEC STD 22 A114	9 / 0
		PASS (QBS)
ESD CDM	Charged Device Model	3 / -
	JEDEC STD 22 C101	3 / -
		3 / -
_atch-up	100mA / 1.5xVddmax	6 / 0
	JEDEC STD 78	PASS (QBS)
Manufacturability	Per assembly site specification	-
Pre-conditioning Level	24h bake @ 125°C,	693 / -
3	192h soak @ 30°C/60%RH,	
	3 IR cycles 260°C + 5/-0°C	
	JEDEC STD 22 A113	
Temperature Cycles	-55°C / +125°C	231 / -
air/air*	JEDEC STD 22 A104	231 / -
		231 / -
Storage*	150°C / No bias	231 / -
	JEDEC STD 22 A103	231 / -
		231 / -
Bias Temperature &	130°C / 85%RH, Vmax	77 / 0
lumidity*	JEDEC STD 22 A101/A110	PASS (QBS)
Jnbiased HAST*	110°C / 85%RH, 3.3psia	231 / -
	JEDEC STD 22 A118	231 / -
Operating Life Test	Dynamic	116 / 0
	140°C (480 Hrs), Vcc Max = 3.6V	116 / 0
	JEDEC STD 22 A108	PASS (QBS)
Thermal Integrity Sequence	level 3 @ 260C +5/-0C	12 / - <b>12 / -</b>
Electrical	Low (minimum) and high (maximum) extremes	30 units minimum
characterization	for device bias voltage and temperature.	
Notes:		

- Qualification tests "pass" on zero fails for each test
- "QBS" stands for Qualification by Similarity

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or to your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com